

Power Supply Test Systems

- Test routines for up to 6 outputs
- Parallel test for higher throughput
- 0V load operation
- Data logging to popular spreadsheet formats
- Interface to automation and HASS systems
- Network support

General Description

The EP-300x Power Supply Test System is based on off-the-shelf instruments from Agilent Technologies, installed in a 6-foot 19" rack. The system incorporates the latest N3300 series electronic loads from Agilent, which operate with full stability at zero volts. The ES-1000 Test Management Software provided with the test system allows up to six UUTs (units-under-test) to be tested in parallel for throughput improvements of three-to-five times over a single-well tester¹. By using standard bench equipment as the base for the test system, cost of calibration and maintenance is lowered. Agilent's proven reliability and our test system's user-friendly diagnostic feature help to minimize system downtime.

The EP-3000 system is designed for the modern high-volume manufacturing environment. Its software can be run from a standalone controller or via the network, and test data is logged in a standard spreadsheet-readable format.

For even higher throughput, our system has interface options



to automated conveyor and HASS (Highly Accelerated Stress Screening) systems.

Test Library

The test library, written in the Agilent VEE Pro Graphical Programming Language, provides most standard DC/DC power supply test functions. Standard tests include voltage regulation, output PARD, input ripple current, switching frequency, short circuit current, low input shutdown, dynamic load, and many more. The ease-of-use of graphical programming means you will be customizing your

own tests to the library in a matter of weeks.

Specifications

Input supply:

DC/DC: 0-80V, 0-30A

AC/DC: Voltage- 300Vrms

Power- 750VA, 1750VA, 3000VA or 4500VA

One to six load outputs:

Voltage: 0-60V

Current: 0-30A, 0-60A or 0-120A

Basic measurement accuracy:

0.002% + 0.6mV, 0.002% + 0.6mA

¹ Actual throughput increase depends on combination of tests.